

<b>Notice of References Cited</b>	Application/Control No. 10/759,642	Applicant(s)/Patent Under Reexamination ERIC YEH ET AL.	
	Examiner Pierre-Louis Desir	Art Unit 2617	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0259531	12-2004	Wood et al.	455/412.1
*	B	US-7,020,685	03-2006	Chen et al.	709/204
*	C	US-2004/0110516	06-2004	Miralles et al.	455/466
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	J	US-			
	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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